

IN THE CLAIMS:

Please amend the claims as indicated below.

- 5 1. (Previously Presented) A method of frequency modification for one or more electronic components in an electronic system, the method comprising the steps of:
- determining, at a particular age of the electronic system, one or more performance parameters for the electronic system, the one or more performance parameters correlated with maximum operating frequency of one or more electronic components of the electronic system for the particular age
- 10 of the electronic system; and
- adjusting an operating frequency of the one or more electronic components from the electronic system in accordance with the one or more performance parameters.
2. (Original) The method of claim 1, wherein the step of adjusting adjusts the operating
- 15 frequency to an adjusted operating frequency, and wherein the adjusted operating frequency is less than or equal to the maximum operating frequency of the one or more electronic components for the particular age of the system.
3. (Original) The method of claim 1, wherein a given one of the one or more performance
- 20 parameters can be converted to a selected operating frequency to be used in the step of adjusting.
4. (Original) The method of claim 3, wherein the given performance parameter comprises a multiplicand used to convert a base frequency to the selected operating frequency to be used in the step of adjusting.
- 25 5. (Original) The method of claim 1, wherein the step of determining a performance parameter further comprises the steps of determining whether the particular age of the electronic system is a predetermined age, and determining an operating frequency from the one or more performance parameters when the particular age is the given age.

6. (Original) The method of claim 5, wherein a given one of the one or more performance parameters comprises a predetermined operating frequency to be used in the steps of determining and adjusting.

5 7. (Original) The method of claim 1, wherein the step of determining, at a particular age of the electronic system, a performance parameter for the electronic system, further comprises the step of gathering, at the particular age of the electronic system, performance statistics from one or more feedback circuits, and determining whether actual performance of the electronic system should be adjusted by using the performance statistics.

10 8. (Original) The method of claim 7, wherein the step of gathering, at the particular age of the electronic system, performance statistics from one or more feedback circuits, further comprises the step of gathering, at the particular age of the electronic system, performance statistics from one or more age-monitoring circuits.

15 9. (Original) The method of claim 8, wherein the step of gathering, at the particular age of the electronic system, performance statistics from one or more age-monitoring circuits further comprises the step of determining, at the particular age of the electronic system, a given performance statistic by comparing speed of an aged circuit with speed of a test circuit that is enabled only for the comparison,
20 wherein the aged circuit has been operated for approximately the particular age.

10. (Original) The method of claim 7, wherein the step of gathering, at the particular age of the electronic system, performance statistics from one or more feedback circuits, further comprises the step of gathering, at the particular age of the electronic system, performance statistics from one or more
25 error detecting circuits.

11. (Original) The method of claim 10, wherein:
the step of gathering further comprises the step of determining that one or more errors have occurred; and

the step of adjusting an operating frequency further comprises the steps of lowering operating frequency from a current operating frequency, beginning execution at a point before the one or more errors occurred, determining if the one or more errors reoccur, and if the one or more errors do not reoccur, leaving the lowered operating frequency as the current operating frequency.

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12. (Original) The method of claim 11, wherein the step of adjusting further comprises, before the step of lowering operating frequency, the steps of beginning execution at a point before the one or more errors occurred, determining if the one or more errors reoccur, and if the one or more errors do not reoccur, leaving current operating frequency alone.

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13. (Original) The method of claim 1, wherein the one or more performance parameters comprise one or more of previous operating frequency, ambient temperature, hours of operation, and supply voltage.

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14. (Previously Presented) The method of claim 1, wherein the one or more performance parameters are stored performance parameters and wherein the method further comprises the step of performing reliability testing to determine wear-out information comprising the stored performance parameters.

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15. (Original) The method of claim 14, wherein the stored performance parameters comprise predetermined ages and predetermined operating frequencies at corresponding ones of the predetermined ages.

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16. (Original) The method of claim 14, wherein the step of performing reliability testing further comprises the step of determining one or more prior operating frequencies of the electronic system, one or more ambient temperatures surrounding the electronic system, and one or more supply voltages of the electronic system.

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17. (Original) The method of claim 16, further comprising the step of providing supply voltage for the electronic system that is higher than nominal supply voltage.

18. (Original) The method of claim 16, further comprising the step of providing ambient temperature surrounding the electronic system that is higher than nominal ambient temperature.

5 19. (Original) The method of claim 1, wherein the performance parameters are received from an external source.

20-28 (Cancelled).